

**Search Notes**

Application/Control No.

10/784,176

Examiner

Tim Heitbrink

Applicant(s)/Patent under  
Reexamination

UCHIYAMA ET AL.

Art Unit

1722

**SEARCHED**

Class	Subclass	Date	Examiner
425	143	5/22/2006	TWH
425	144	5/22/2006	TWH
264	40.6	5/22/2006	TWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR